

HB56D51236 Series

524,288-Word x 36-Bit High Density Dynamic RAM Module

DESCRIPTION

The HB56D51236B is a 512k x 36 dynamic RAM module, mounted 16 pieces of 1 Mbit DRAM (HM514256JP) sealed in SOJ package and 8 pieces of 256k-bit DRAM (HM51256CP) sealed in PLCC package. An outline of the HB56D51236B is 72-pin single in-line package. Therefore, the HB56D51236B makes high density mounting possible without surface mount technology. The HB56D51236B provides common data inputs and outputs. Decoupling capacitors are mounted beneath each SOJ and PLCC but only on the one side of its module board.

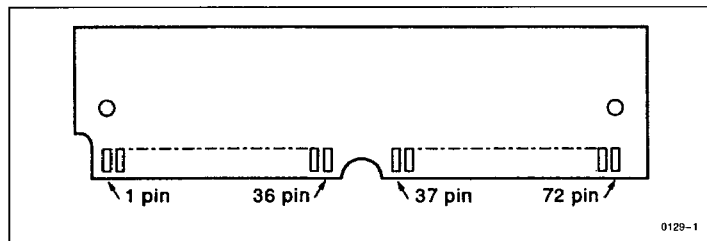
FEATURES

- 72-pin Single In-line Package
 - Lead Pitch 1.27mm
- Single 5V ($\pm 5\%$) Supply
- High Speed
 - Access Time 85 ns/100 ns/120 ns (max)
- Low Power Dissipation
 - Active Mode 4.58W/3.91W/3.36W (max)
 - Standby Mode 252 mW (max)
- Fast Page Mode Capability
- 512 Refresh Cycle (8 ms)
- 2 Variations of Refresh
 - RAS Only Refresh
 - CAS Before RAS Refresh
- TTL Compatible

ORDERING INFORMATION

Part No.	Access Time	Package
HB56D51236B-85	85 ns	72-pin SIP Socket Type
HB56D51236B-10	100 ns	
HB56D51236B-12	120 ns	

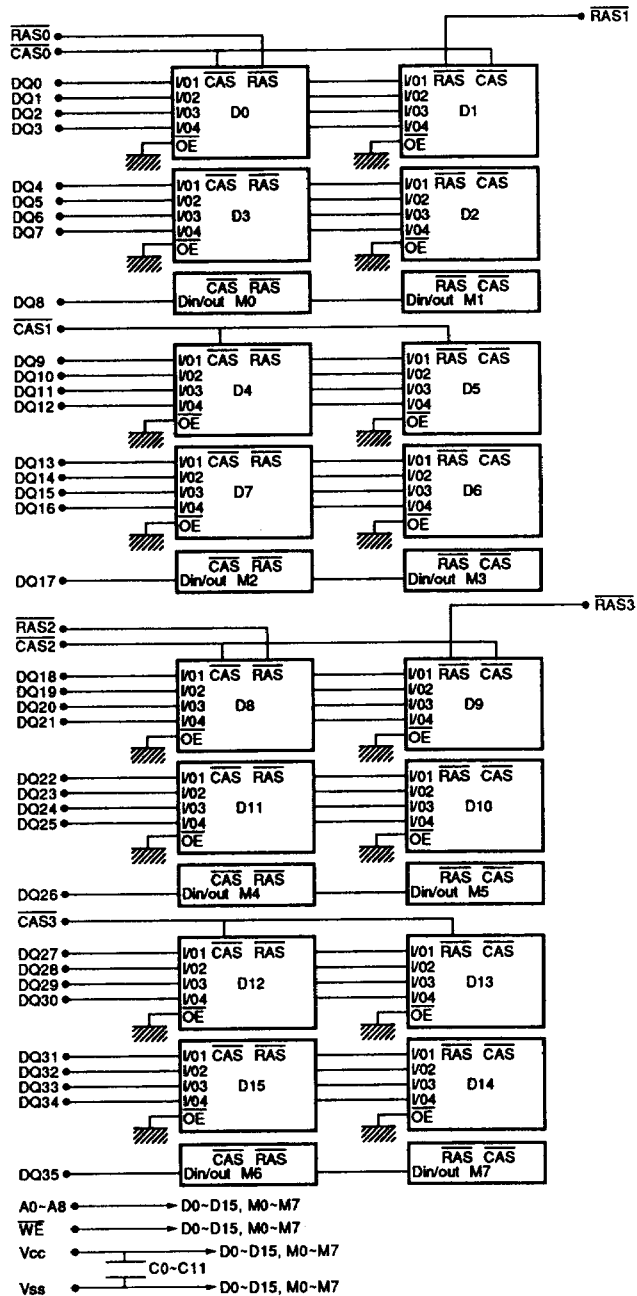
PIN OUT



Pin No.	Pin Name	Pin No.	Pin Name
1	V _{SS}	37	DQ ₁₇
2	DQ ₀	38	DQ ₃₅
3	DQ ₁₈	39	V _{SS}
4	DQ ₁	40	CAS ₀
5	DQ ₁₉	41	CAS ₂
6	DQ ₂	42	CAS ₃
7	DQ ₂₀	43	CAS ₁
8	DQ ₃	44	RAS ₀
9	DQ ₂₁	45	RAS ₁
10	V _{CC}	46	NC
11	NC	47	WE
12	A ₀	48	NC
13	A ₁	49	DQ ₉
14	A ₂	50	DQ ₂₇
15	A ₃	51	DQ ₁₀
16	A ₄	52	DQ ₂₈
17	A ₅	53	DQ ₁₁
18	A ₆	54	DQ ₂₉
19	NC	55	DQ ₁₂
20	DQ ₄	56	DQ ₃₀
21	DQ ₂₂	57	DQ ₁₃
22	DQ ₅	58	DQ ₃₁
23	DQ ₂₃	59	V _{CC}
24	DQ ₆	60	DQ ₃₂
25	DQ ₂₄	61	DQ ₁₄
26	DQ ₇	62	DQ ₃₃
27	DQ ₂₅	63	DQ ₁₅
28	A ₇	64	DQ ₃₄
29	NC	65	DQ ₁₆
30	V _{CC}	66	NC
31	A ₈	67	PD ₁
32	NC	68	PD ₂
33	RAS ₃	69	PD ₃
34	RAS ₂	70	PD ₄
35	DQ ₂₆	71	NC
36	DQ ₈	72	V _{SS}



■ BLOCK DIAGRAM

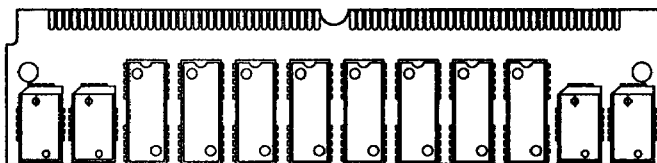
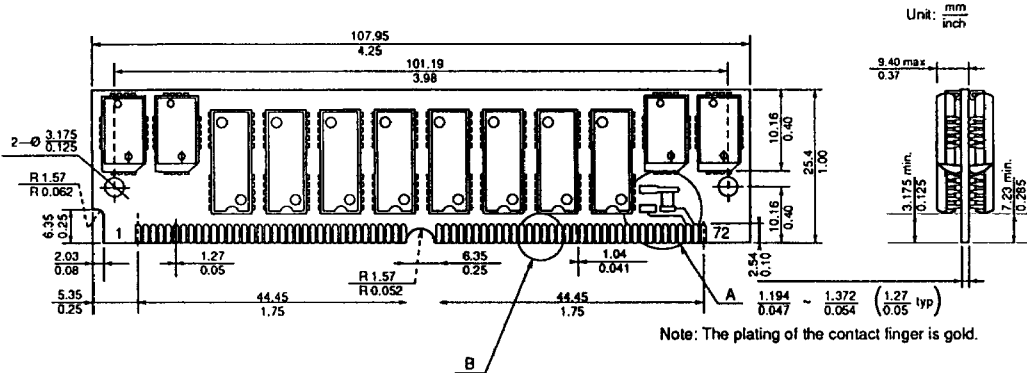


*D0~D15: HM514256JP
 M0~M7: HM51256CP

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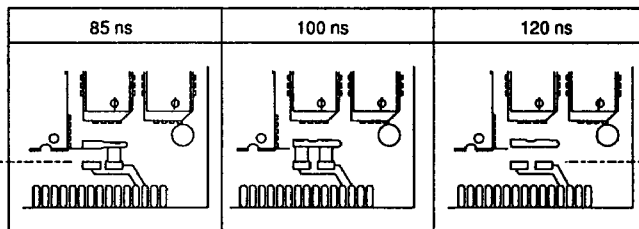


■ PHYSICAL OUTLINE



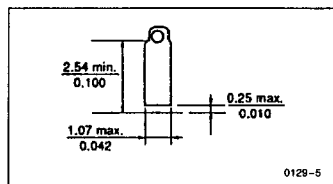
0129-3

Detail A



0129-4

Detail B



■ PIN DESCRIPTION

Pin Name	Function
A ₀ –A ₈	Address Input
A ₀ –A ₈	Refresh Address Input
DQ ₀ –DQ ₃₅	Data-in/Data-out
CAS ₀ –CAS ₃	Column Address Strobe
RAS ₀ –RAS ₃	Row Address Strobe
WE	Read/Write Enable
V _{CC}	Power Supply (+ 5V)
V _{SS}	Ground
PD ₁ –PD ₄	Presence Detect Pin
NC	Non-Connection

■ PRESENCE DETECT PIN OUT

Pin No.	Pin Name	HB56D51236B		
		85 ns	100 ns	120 ns
67	PD ₁	NC	NC	NC
68	PD ₂	V _{SS}	V _{SS}	V _{SS}
69	PD ₃	NC	V _{SS}	NC
70	PD ₄	V _{SS}	V _{SS}	NC

■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Voltage on Any Pin Relative to V _{SS}	(Input)	V _{in}	– 1.0 to + 7.0
	(Output)	V _{out}	– 1.0 to + 7.0
Supply Voltage Relative to V _{SS}	V _{CC}	– 1.0 to + 7.0	V
Short Circuit Output Current	I _{out}	50	mA
Power Dissipation	P _T	12	W
Operating Temperature	T _{opr}	0 to + 70	°C
Storage Temperature	T _{stg}	– 55 to + 125	°C

■ ELECTRICAL CHARACTERISTICS

• Recommended DC Operating Conditions (T_A = 0 to + 70°C)

Parameter	Symbol	Min	Typ	Max	Unit	Note
Supply Voltage	V _{SS}	0	0	0	V	
	V _{CC}	4.75	5.0	5.25	V	1
Input High Voltage	V _{IH}	2.4	—	5.5	V	1
Input Low Voltage	V _{IL}	– 1.0	—	0.8	V	1

Note: 1. All voltage referenced to V_{SS}.

• DC Electrical Characteristics ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$, $V_{SS} = 0\text{V}$)

Parameter	Symbol	HB56D51236B-85		HB56D51236B-10		HB56D51236B-12		Unit	Test Conditions	Note
		Min	Max	Min	Max	Min	Max			
Operating Current	I_{CC1}	—	872	—	744	—	640	mA	$t_{RC} = \text{Min}$	1, 2
Standby Current	I_{CC2}	—	48	—	48	—	48	mA	TTL Interface $\overline{\text{RAS}}, \overline{\text{CAS}} = V_{IH}$, $D_{out} = \text{High-Z}$	
		—	24	—	24	—	24	mA	CMOS Interface $\overline{\text{RAS}}$, $\overline{\text{CAS}} \geq V_{CC} - 0.2\text{V}$, $D_{out} = \text{High-Z}$	
$\overline{\text{RAS}}$ Only Refresh Current	I_{CC3}	—	872	—	744	—	640	mA	$t_{RC} = \text{Min}$	2
Standby Current	I_{CC5}	—	128	—	128	—	128	mA	$\overline{\text{RAS}} = V_{IH}$, $\overline{\text{CAS}} = V_{IL}$, $D_{out} = \text{Enable}$	1
$\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Current	I_{CC6}	—	832	—	724	—	620	mA	$t_{RC} = \text{Min}$	
Page Mode Current	I_{CC7}	—	828	—	744	—	640	mA	$t_{PC} = \text{Min}$	1, 3
Input Leakage Current	I_{LI}	-10	10	-10	10	-10	10	μA	$0\text{V} \leq V_{in} \leq 7\text{V}$	
Output Leakage Current	I_{LO}	-10	10	-10	10	-10	10	μA	$0\text{V} \leq V_{out} \leq 7\text{V}$, $D_{out} = \text{Disable}$	
Output High Voltage	V_{OH}	2.4	V_{CC}	2.4	V_{CC}	2.4	V_{CC}	V	High $I_{out} = -5\text{mA}$	
Output Low Voltage	V_{OL}	0	0.4	0	0.4	0	0.4	V	Low $I_{out} = 4.2\text{mA}$	

Notes: 1. I_{CC} depends on output load condition when the device is selected, $I_{CC}(\text{max})$ is specified at the output open condition.
 2. Address can be changed less than three times while $\overline{\text{RAS}} = V_{IL}$.
 3. Address can be changed once or less while $\overline{\text{CAS}} = V_{IH}$.

• Capacitance ($T_A = 25^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 5\%$)

Parameter	Symbol	Typ	Max	Unit	Note
Input Capacitance (Address)	C_{I1}	—	161	pF	1
Input Capacitance ($\overline{\text{WE}}$)	C_{I2}	—	193	pF	1
Input Capacitance ($\overline{\text{RAS}}, \overline{\text{CAS}}$)	C_{I3}	—	62	pF	1
Output Capacitance ($DQ_0-7, DQ_9-16, DQ_{18-25}, DQ_{27-34}$)	$C_{I/O1}$	—	29	pF	1, 2
Output Capacitance ($DQ_8, 17, 26, 35$)	$C_{I/O2}$	—	39	pF	1, 2

Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.
 2. $\overline{\text{CAS}} = V_{IH}$ to disable D_{out} .

• AC Characteristics ($T_A = 0$ to $+70^\circ\text{C}$, $V_{CC} = 5V \pm 5\%$, $V_{SS} = 0V$)^{1, 12}

Read, Write and Refresh Cycle (Common Parameters)

Parameter	Symbol	HB56D51236B-85		HB56D51236B-10		HB56D51236B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t_{RC}	160	—	190	—	220	—	ns	
RAS Precharge Time	t_{RP}	70	—	80	—	90	—	ns	
RAS Pulse Width	t_{RAS}	80	10000	100	10000	120	10000	ns	
CAS Pulse Width	t_{CAS}	25	10000	25	10000	30	10000	ns	
Row Address Setup Time	t_{ASR}	0	—	0	—	0	—	ns	
Row Address Hold Time	t_{RAH}	12	—	15	—	15	—	ns	
Column Address Setup Time	t_{ASC}	0	—	0	—	0	—	ns	
Column Address Hold Time	t_{CAH}	20	—	20	—	25	—	ns	
Column Address Hold Time to $\overline{\text{RAS}}$	t_{AR}	60	—	75	—	90	—	ns	
RAS to CAS Delay Time	t_{RCD}	22	55	25	75	25	90	ns	8
RAS to Column Address Delay Time	t_{RAD}	17	45	20	55	20	65	ns	9
RAS Hold Time	t_{RSH}	25	—	25	—	30	—	ns	
CAS Hold Time	t_{CSH}	85	—	100	—	120	—	ns	
CAS to RAS Precharge Time	t_{CRP}	10	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t_T	3	50	3	50	3	50	ns	7
Refresh Period	t_{REF}	—	8	—	8	—	8	ns	15

Read Cycle

Parameter	Symbol	HB56D51236B-85		HB56D51236B-10		HB56D51236B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Access Time from $\overline{\text{RAS}}$	t_{RAC}	—	85	—	100	—	120	ns	2, 3
Access Time from $\overline{\text{CAS}}$	t_{CAC}	—	25	—	25	—	30	ns	3, 4
Access Time from Address	t_{AA}	—	40	—	45	—	55	ns	3, 5
Read Command Setup Time	t_{RCS}	0	—	0	—	0	—	ns	
Read Command Hold Time to CAS	t_{RCH}	0	—	0	—	0	—	ns	
Read Command Hold Time to $\overline{\text{RAS}}$	t_{RRH}	10	—	10	—	10	—	ns	
Column Address to RAS Lead Time	t_{RAL}	40	—	45	—	55	—	ns	
Output Buffer Turn-off Time	t_{OFF}	0	20	0	25	0	30	ns	6

Write Cycle

Parameter	Symbol	HB56D51236B-85		HB56D51236B-10		HB56D51236B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Write Command Setup Time	t_{WCS}	0	—	0	—	0	—	ns	10
Write Command Hold Time	t_{WCH}	20	—	25	—	30	—	ns	
Write Command Hold Time to $\overline{\text{RAS}}$	t_{WCR}	65	—	80	—	95	—	ns	
Write Command Pulse Width	t_{WP}	15	—	20	—	25	—	ns	
Data-in Setup Time	t_{DS}	0	—	0	—	0	—	ns	11
Data-in Hold Time	t_{DH}	20	—	20	—	25	—	ns	11
Data-in Hold Time to $\overline{\text{RAS}}$	t_{DHR}	60	—	75	—	90	—	ns	



Refresh Cycle

Parameter	Symbol	HB56D51236B-85		HB56D51236B-10		HB56D51236B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
CAS Setup Time (CAS Before RAS Refresh Cycle)	t _{CSR}	10	—	10	—	10	—	ns	
CAS Hold Time (CAS Before RAS Refresh Cycle)	t _{CHR}	20	—	20	—	25	—	ns	
RAS Precharge to CAS Hold Time	t _{RPC}	15	—	15	—	15	—	ns	

Fast Page Mode Cycle

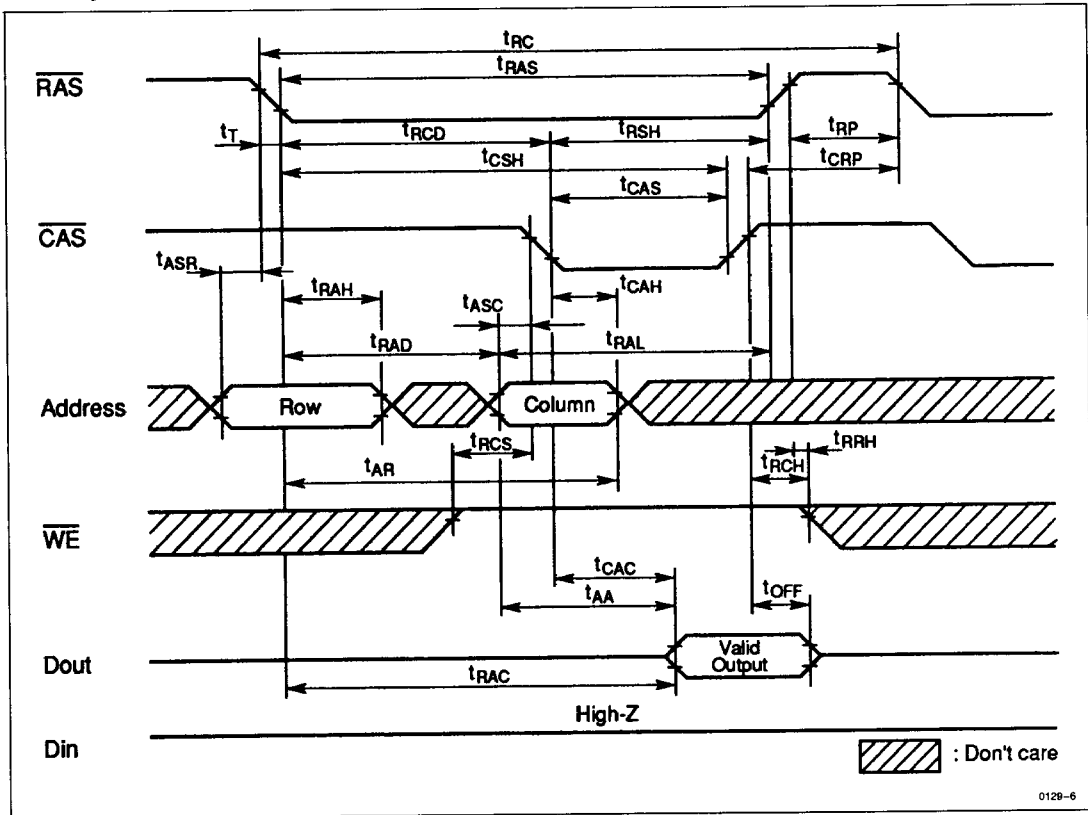
Parameter	Symbol	HB56D51236B-85		HB56D51236B-10		HB56D51236B-12		Unit	Note
		Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	t _{PC}	55	—	55	—	65	—	ns	
Fast Page Mode CAS Precharge Time	t _{CP}	10	—	15	—	20	—	ns	
Fast Page Mode RAS Pulse Width	t _{RASC}	80	100000	100	100000	120	100000	ns	13
Access Time from CAS Precharge	t _{ACP}	—	50	—	50	—	60	ns	14
RAS Hold Time from CAS Precharge	t _{RHCP}	50	—	50	—	60	—	ns	

- Notes:
1. AC measurements assume $t_T = 5$ ns.
 2. Assumes that $t_{RCD} \leq t_{RCD}(\text{max})$ and $t_{RAD} \leq t_{RAD}(\text{max})$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
 3. Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
 4. Assumes that $t_{RCD} \geq t_{RCD}(\text{max})$ and $t_{RAD} \leq t_{RAD}(\text{max})$.
 5. Assumes that $t_{RCD} \leq t_{RCD}(\text{max})$ and $t_{RAD} \geq t_{RAD}(\text{max})$.
 6. $t_{OFF}(\text{max})$ defines the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
 7. $V_{IH}(\text{min})$ and $V_{IL}(\text{max})$ are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
 8. Operation with the $t_{RCD}(\text{max})$ limit insures that $t_{RAC}(\text{max})$ can be met, $t_{RCD}(\text{max})$ is specified as a reference point only, if t_{RCD} is greater than the specified $t_{RCD}(\text{max})$ limit, then access time is controlled exclusively by t_{CAC} .
 9. Operation with the $t_{RAD}(\text{max})$ limit insures that $t_{RAC}(\text{max})$ can be met, $t_{RAD}(\text{max})$ is specified as a reference point only, if t_{RAD} is greater than the specified $t_{RAD}(\text{max})$ limit, then access time is controlled exclusively by t_{AA} .
 10. Early write cycle only ($t_{WCS} \geq t_{WCS}(\text{min})$).
 11. These parameters are referenced to CAS leading edge in an early write cycle.
 12. An initial pause of 100 μ s is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing RAS clock such as RAS only refresh).
 13. t_{RASC} defines RAS pulse width in fast page mode cycles.
 14. Access time is determined by the longer of t_{AA} or t_{CAC} or t_{ACP} .
 15. t_{REF} is defined as 512 refresh cycles.

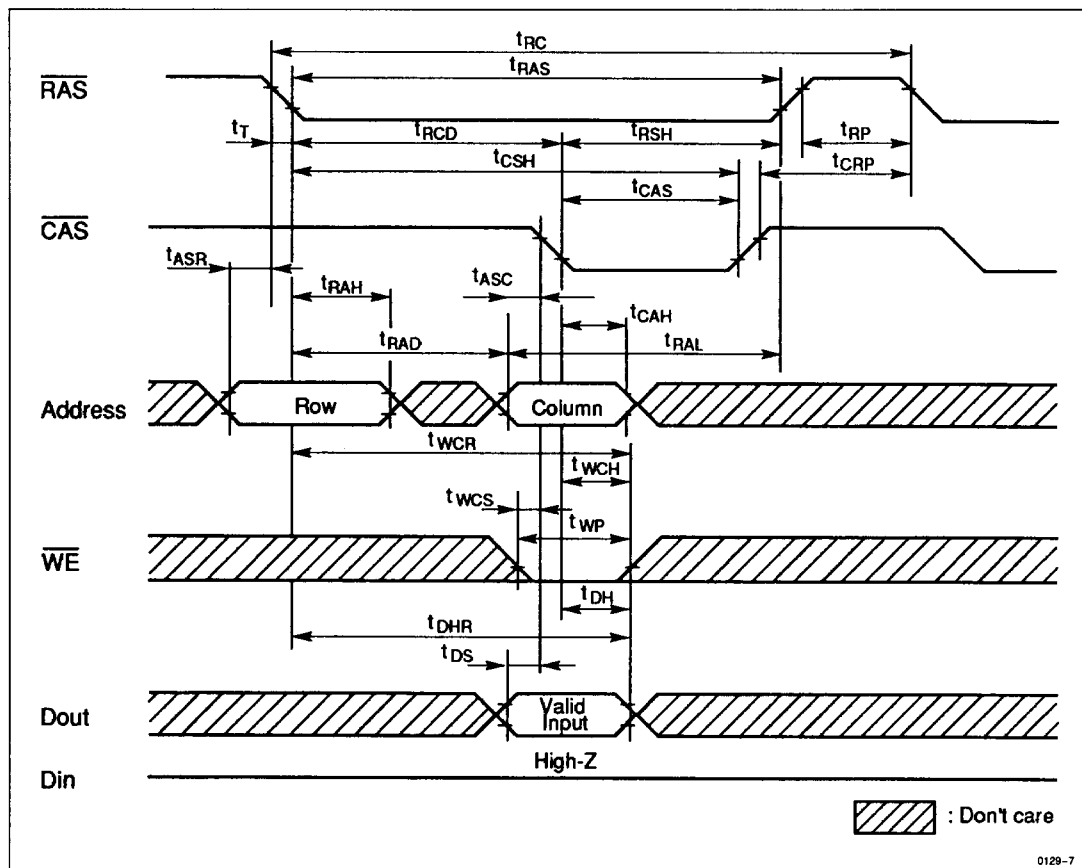


TIMING WAVEFORMS

Read Cycle

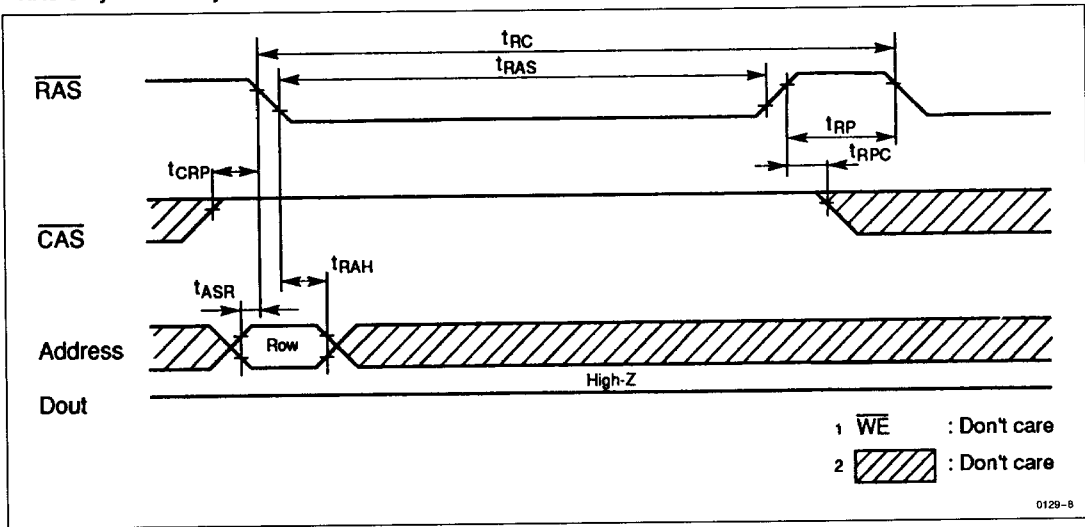
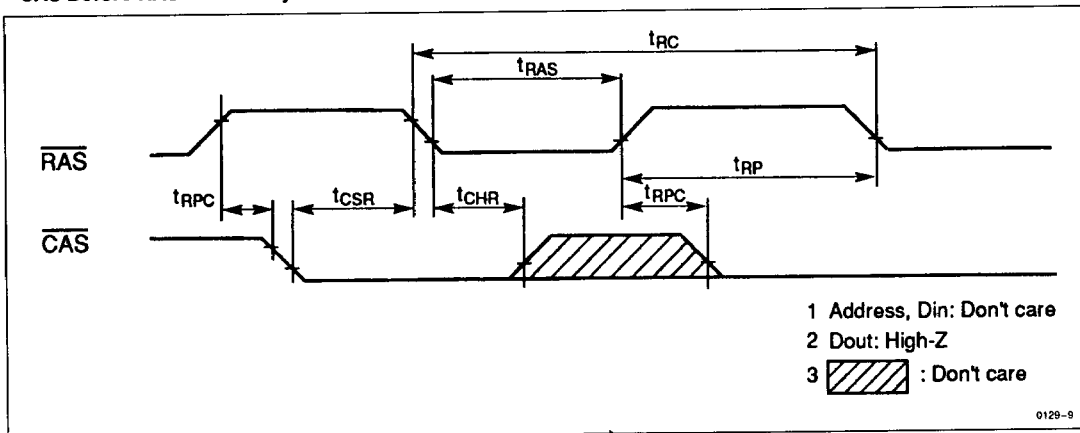


• Early Write Cycle

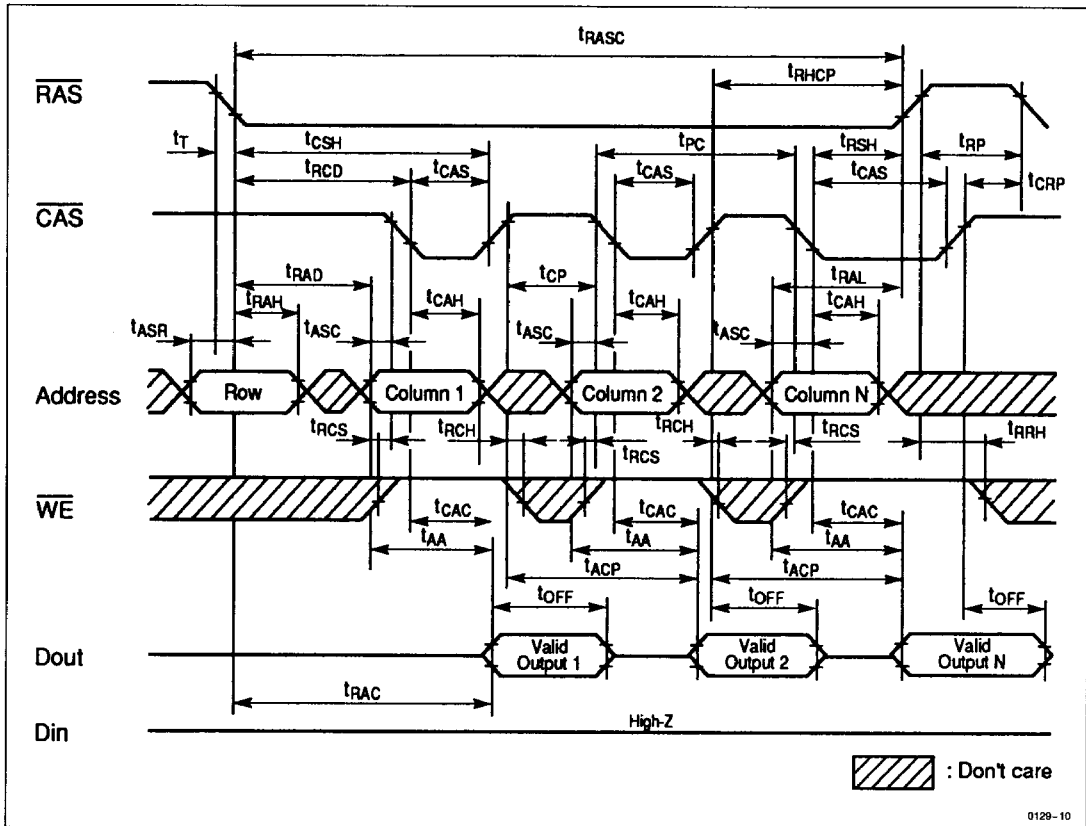


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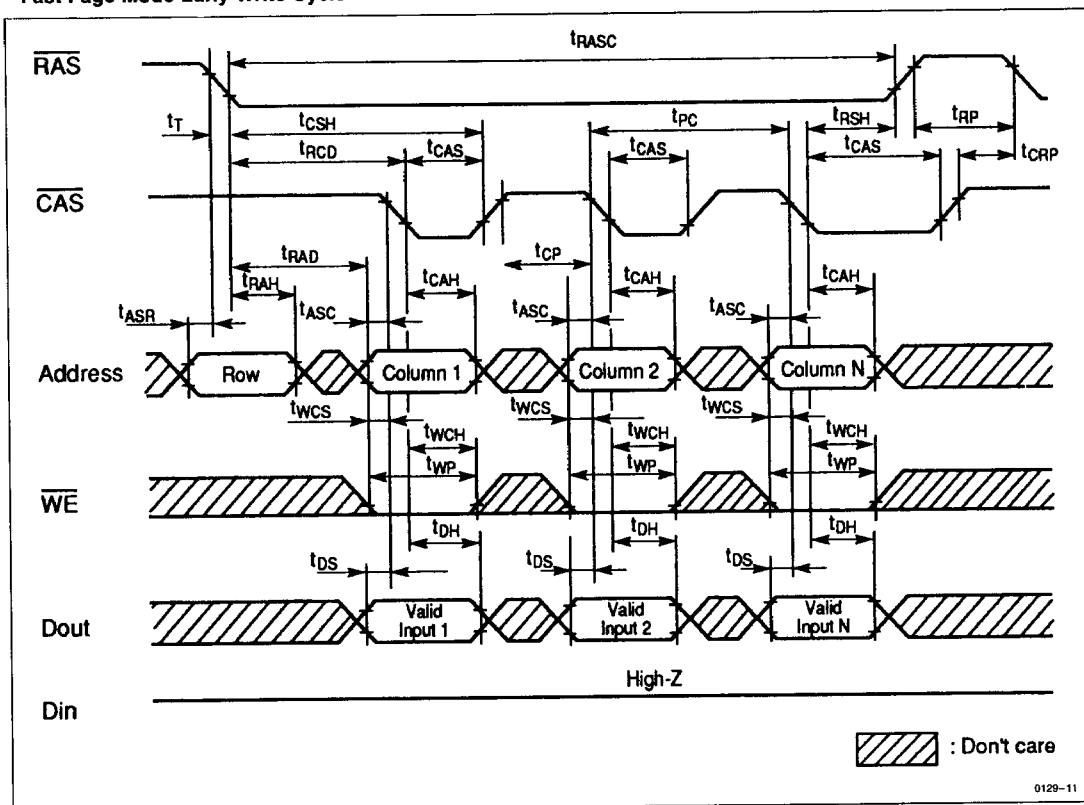
• $\overline{\text{RAS}}$ Only Refresh Cycle• $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle

• Fast Page Mode Read Cycle



0129-10

• Fast Page Mode Early Write Cycle



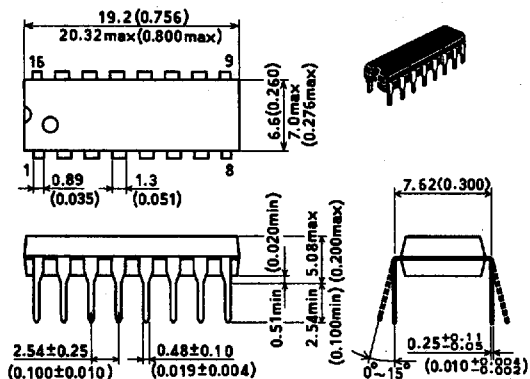
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T-90-20

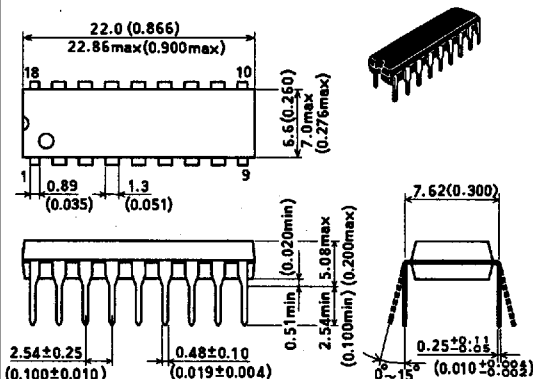
Unit: mm (inch) Scale 3/2

• Dual-in-line Plastic

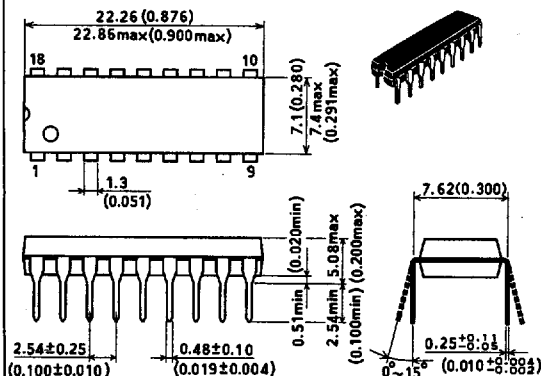
• DP-16B



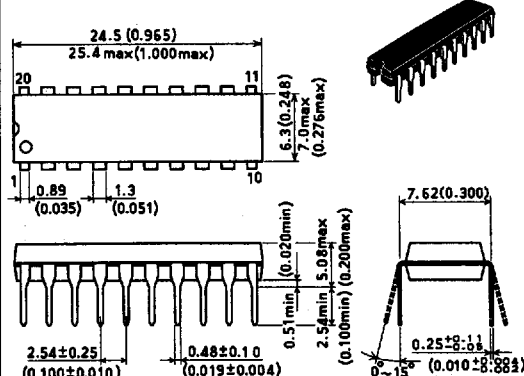
• DP-18B



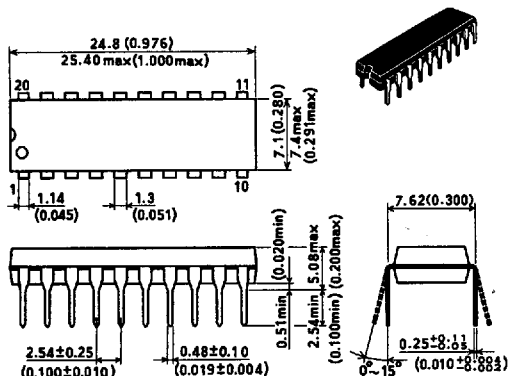
• DP-18C



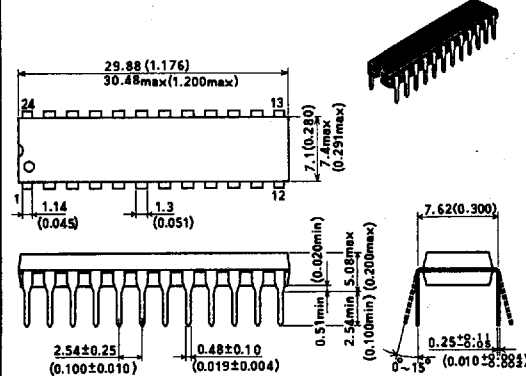
• DP-20N



• DP-20NA



• DP-20NC

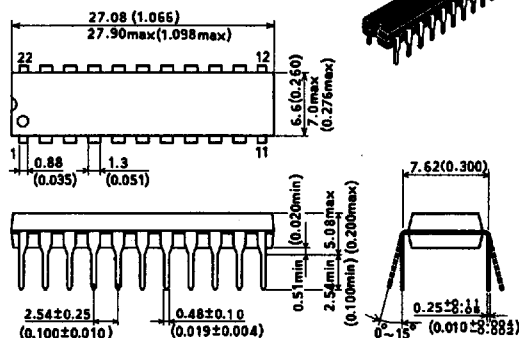


• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

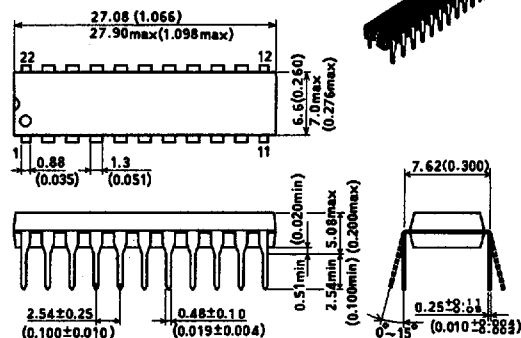
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• DP-22N

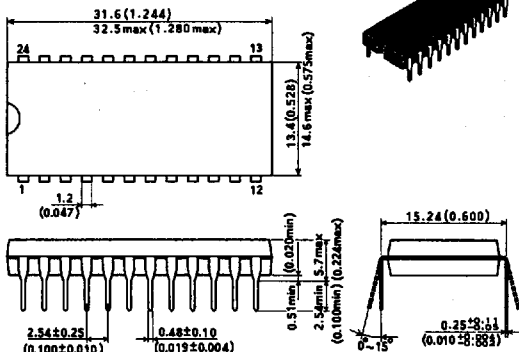


• DP-22NB

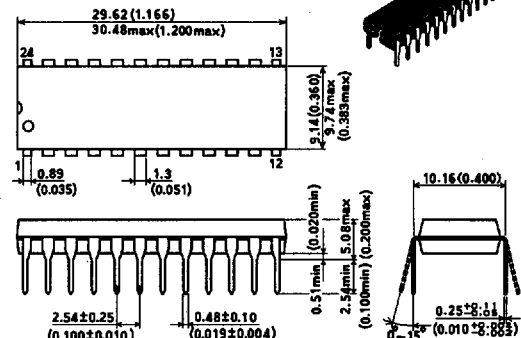
T-90-20



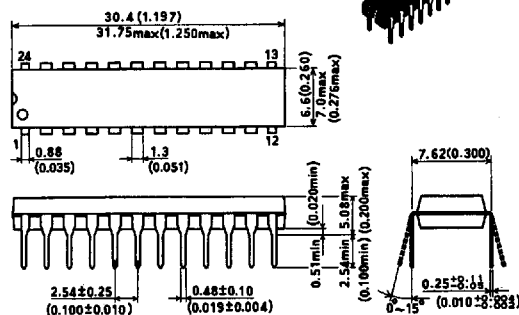
• DP-24



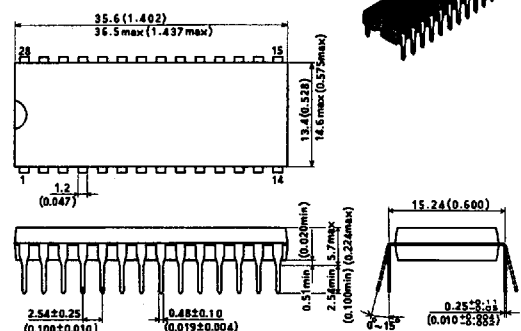
• DP-24A



• DP-24N



• DP-28

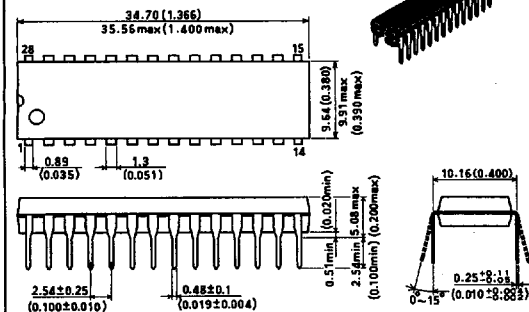


• Dual-in-line Plastic

HITACHI/ LOGIC/ARRAYS/MEM

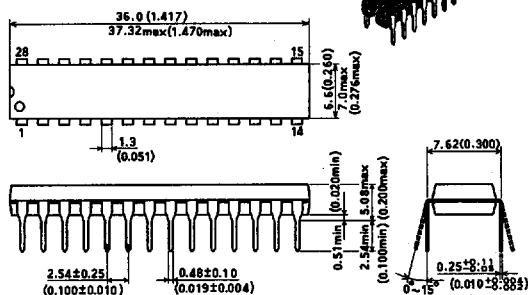
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• DP-28C

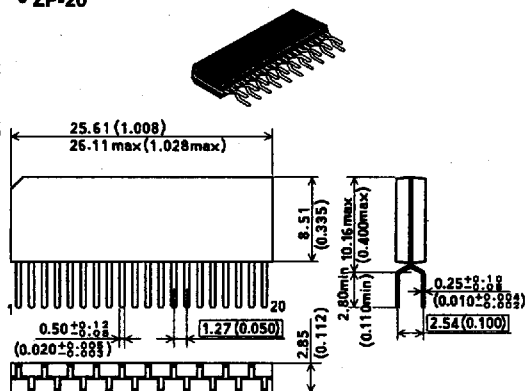


• DP-28N

T-90-20

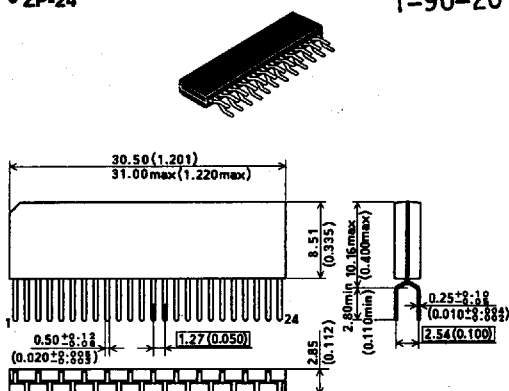


• ZP-20

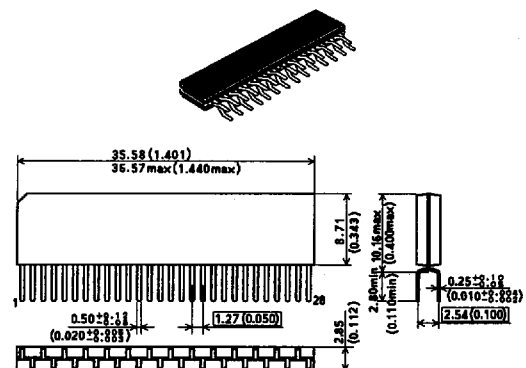


• ZP-24

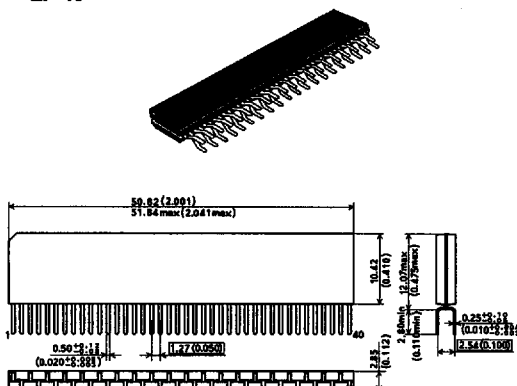
T-90-20



• ZP-28



• ZP-40



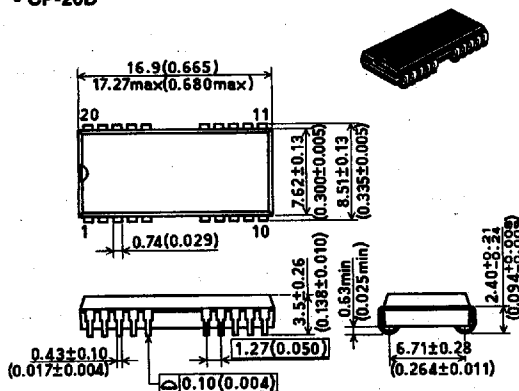
• Flat Package (J-bend Leads)

HITACHI/ LOGIC/ARRAYS/MEM

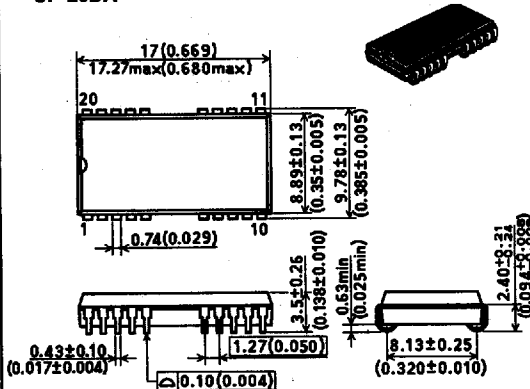
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T-90-20

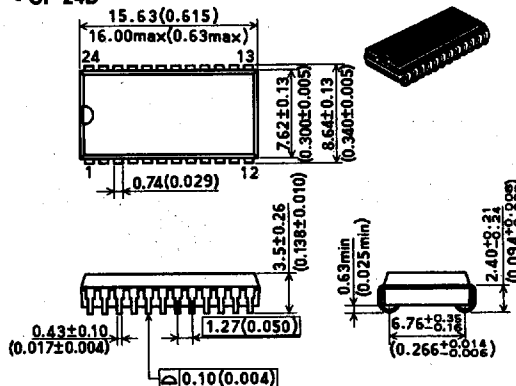
• CP-20D



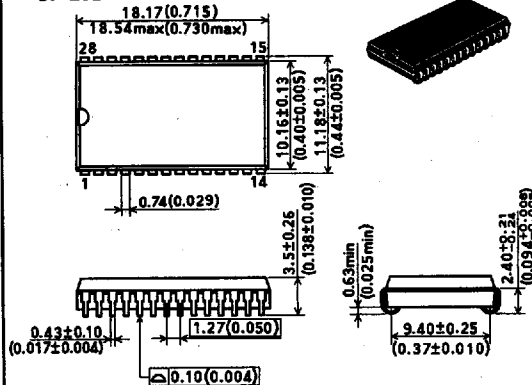
• CP-20DA



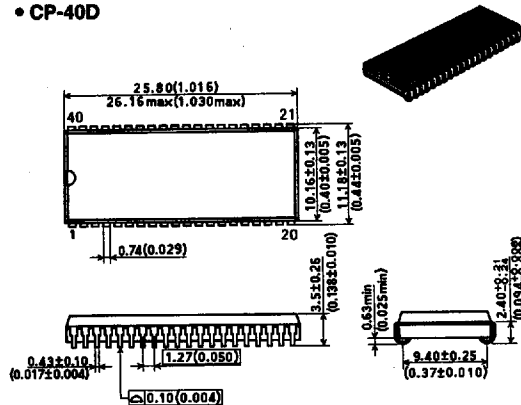
• CP-24D



• CP-28D



• CP-40D

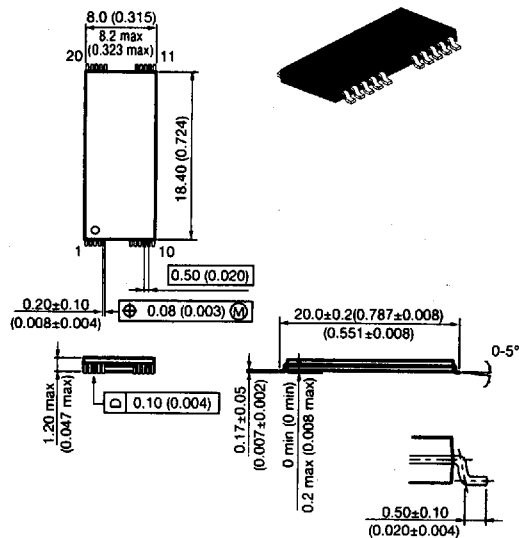


• TSOP (Thin Small Outline Package)

HITACHI/ LOGIC/ARRAYS/MEM

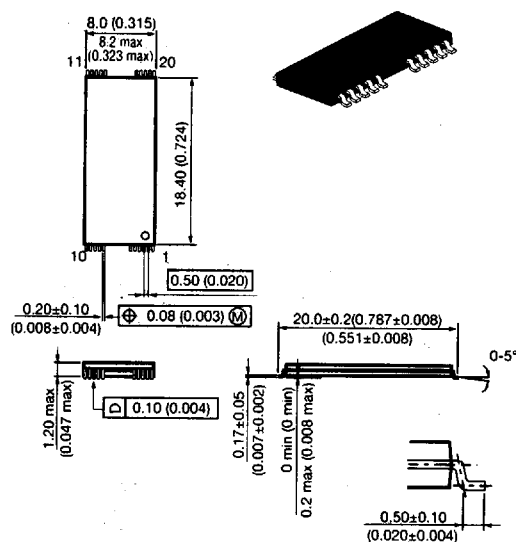
Unit: mm (inch) Scale 3/2

• TFP-20DA

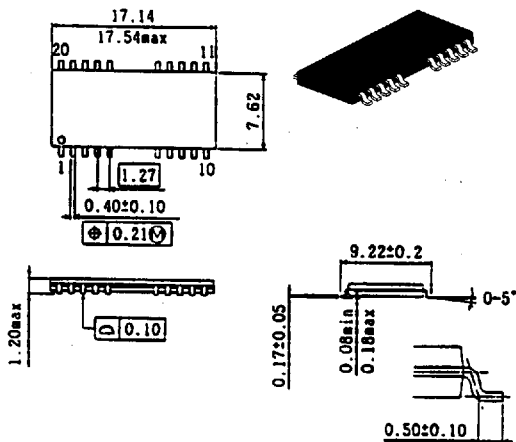


• TFP-20DAR

T-90-20



• TTP-20D



• TTP-20DR

